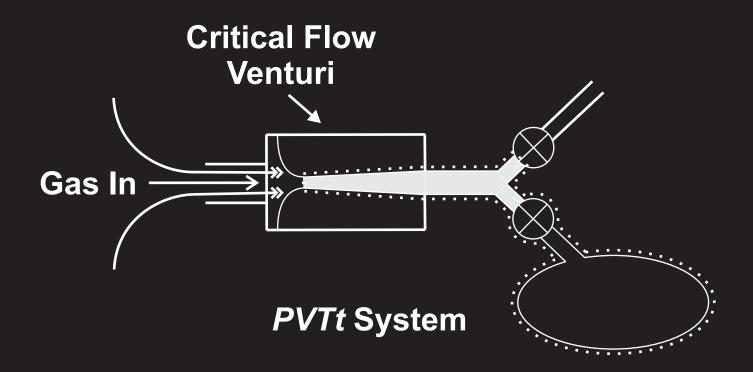
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- Statistical Engineering

flow standard. A <i>PVTt</i> stan- period and determines the d new <i>PVTt</i> standard with unc	dard diverts gas from a meter ensity change in the volume vertainties as low as 0.02 % are	sure, volume, temperature, and time (<i>PVTt</i>) primary gas under test into a known volume for a measured time a pressure and temperature measurements. Details of a given in the article by Wright, Johnson, and Moldover <i>Tt</i> Gas Flow Standard." Cover illustration arranged by
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